	Type	Hits	Search Text	DBs	Time Stamp	Comments	Error Defin	Errors	Ref #
1	BRS	207	semiconductor and characteristic and fabricate and substrate and classify$3	US-PGPUB; USPAT	2005/05/31 08:24				S1
2	BRS	692	mahalanobis	US-PGPUB; USPAT	2005/05/31 08:24				S2
3	BRS	0	S1 and S2	US-PGPUB; USPAT	2005/05/31 08:24				S3
4	BRS	113	S2 and semiconductor	US-PGPUB; USPAT	2005/05/31 08:24				S4
5	BRS	61	S4 and classify$3	US-PGPUB; USPAT	2005/05/31 08:25				S5
6	BRS	53	S5 and test	US-PGPUB; USPAT	2005/05/31 08:25				S6
7	BRS	50	S6 and distance and compar$3	US-PGPUB; USPAT	2005/05/31 08:25				S7
8	BRS	47	S7 and space	US-PGPUB; USPAT	2005/05/31 08:25				S8
9	BRS	6	S8 and fabricate$3	US-PGPUB; USPAT	2005/05/31 08:28				S9
10	BRS	5310	semiconductor and classify$3	US-PGPUB; USPAT	2005/05/31 08:28				S10
11	BRS	32	S10 and test near1 element and substrate	US-PGPUB; USPAT	2005/05/31 08:32				S11
12	BRS	1	S11 and mahalanobis	US-PGPUB; USPAT	2005/05/31 08:51				S12
13	BRS	0	mahalanobis and classify$3 near1 semiconductor	US-PGPUB; USPAT	2005/05/31 08:52				S13
14	BRS	113	mahalanobis and semiconductor	US-PGPUB; USPAT	2005/05/31 08:52				S14
15	BRS	749103	14a dn fabricat$3	US-PGPUB; USPAT	2005/05/31 08:53				S15
16	BRS	18	S14 and fabricat$3	US-PGPUB; USPAT	2005/06/08 19:09				S16

	U		Document ID	Issue Date	Pages	Title	Current OR	Current XRe	Retrieval	Inventor	S	C	P		
1			US 20050074834 A1	20050407	144	Method and system for classifying a scenario	435/34	702/19		Chaplen, Frank W.R. et al.					
2			US 20050028932 A1	20050210	40	Method and apparatus for real-time dynamic chemical analysis	156/345.15			Shekel, Yehuda et al.					
3			US 20040228186 A1	20041118	19	Analysis method for semiconductor device, analysis system and a computer program product	365/202			Kadota, Kenichi					
4			US 20040219590 A1	20041104	56	Methods of detecting targets on an arrary	435/6	435/287.2		Dickinson, Todd et al.					
5			US 20030059104 A1	20030327	18	Pattern evaluation system, pattern evaluation method and program	382/145	382/192		Mitsui, Tadashi					
6			US 20020193891 A1	20021219	28	Apparatus for diagnosing failure in equipment using signals relating to the equipment	700/21	700/17; 700/79; 700/80; 700/83		Ushiku, Yukihiro					
7			US 20020156549 A1	20021024	22	Controlling method for manufacturing process	700/108	700/111; 700/116; 700/262		Hayashi, Shunji					
8			US 20020154315 A1	20021024	43	Optical computational system	356/305	359/326		Myrick, Michael L.					
9			US 20020102578 A1	20020801	56	Alternative substrates and formats for bead-based array of arrays TM	435/6	435/287.2		Dickinson, Todd et al.					
10			US 20010020284 A1	20010906	43	Method and device for analyzing data	714/37			Tsuda, Hidetaka et al.					
11			US 6862484 B2	20050301	22	Controlling method for manufacturing process	700/73	700/110; 700/121;		Hayashi; Shunji					

						702/185; 702/83; 702/84			
12	US 6782348 B2	20040824	28	Apparatus for diagnosing failure in equipment using signals relating to the equipment	702/183	700/121; 702/185; 702/33; 702/34; 702/35; 702/57; 702/58; 714/48		Ushiku; Yukihiro	
13	US 6770441 B2	20040803	53	Array compositions and methods of making same	435/6	422/102; 422/68.1; 435/283.1; 435/287.2; 435/287.8; 435/288.2; 435/288.3; 435/288.4; 435/288.5; 435/7.1		Dickinson; Todd et al.	
14	US 6741341 B2	20040525	27	Reentry vehicle interceptor with IR and variable FOV laser radar	356/141.1	250/203.6; 250/342; 356/139.04; 356/139.07; 356/4.01		DeFlumere; Michael E.	
15	US 6629090 B2	20030930	43	method and device for analyzing data	706/47			Tsuda; Hidetaka et al.	
16	US 6529276 B1	20030304	42	Optical computational system	356/419	356/310; 356/330; 706/40		Myrick; Michael L.	
17	US 5757001 A	19980526	27	Detection of counterfeit currency	250/339.11	250/339.09; 250/341.8		Burns; Donald A.	
18	US 4975581 A	19901204	22	Method of and apparatus for determining the similarity of a biological analyte from a model constructed from known biological fluids	250/339.09	250/339.11; 250/339.12; 250/343; 600/331; 702/19		Robinson; Mark R. et al.	

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definiti	Er
1*	IS&R	L1	2	(("5274434") or ("5726920")).PN.	US-PG PUB; USPAT	2005/06/08 16:25			
2	IS&R	L4	1	("6438440").PN.	US-PG PUB; USPAT	2005/06/08 19:09			